TOSHIBA

TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74HCT00AP,TC74HCT00AF,TC74HCT00AFN

Quad 2-Input NAND Gate

The TC74HCT00A is a high speed CMOS 2-INPUT NAND GATE fabricated with silicon gate C^2MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

This device may be used as a level converter for interfacing TTL or NMOS to High Speed CMOS. The inputs are compatible with TTL, NMOS and CMOS output voltage levels.

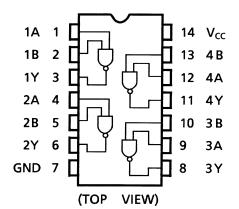
The internal circuit is composed of 3 stages including buffer output, which provide high noise immunity and stable output.

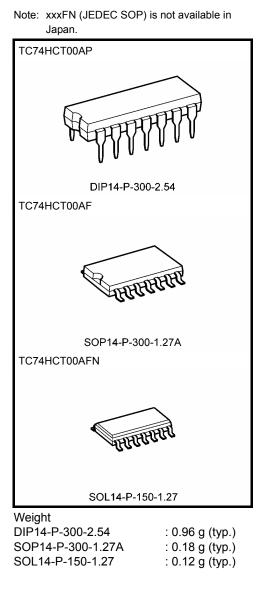
All inputs are equipped with protection circuits against static discharge or transient excess voltage.

Features

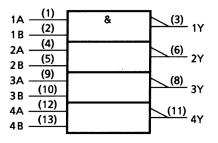
- High speed: $t_{pd} = 10 \text{ ns}$ (typ.) at $V_{CC} = 5 \text{ V}$
- Low power dissipation: $I_{CC} = 1 \ \mu A \ (max)$ at $Ta = 25^{\circ}C$
- Compatible with TTL outputs: $V_{IH} = 2 V (min)$ $V_{IL} = 0.8 V (max)$
- Wide interfacing ability: LSTTL, NMOS, CMOS
- Output drive capability: 10 LSTTL loads
- Symmetrical output impedance: |IOH| = IOL = 4 mA (min)
- Balanced propagation delays: $t_{pLH} \simeq t_{pHL}$
- Pin and function compatible with 74LS00

Pin Assignment





IEC Logic Symbol



Truth Table

А	В	Y
L	L	Н
L	Н	Н
Н	L	Н
Н	Н	L

Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V _{CC}	-0.5~7	V
DC input voltage	V _{IN}	$-0.5 \sim V_{CC} + 0.5$	V
DC output voltage	V _{OUT}	$-0.5 \sim V_{CC} + 0.5$	V
Input diode current	I _{IK}	±20	mA
Output diode current	IOK	±20	mA
DC output current	IOUT	±25	mA
DC V _{CC} /ground current	ICC	±50	mA
Power dissipation	PD	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	T _{stg}	-65~150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of Ta = -40 to 65° C. From Ta = 65 to 85° C a derating factor of -10 mW/°C shall be applied until 300 mW.

Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	V _{CC}	4.5~5.5	V
Input voltage	V _{IN}	0~V _{CC}	V
Output voltage	Vout	0~V _{CC}	V
Operating temperature	T _{opr}	-40~85	°C
Input rise and fall time	t _r , t _f	0~500	ns

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

Electrical Characteristics

DC Characteristics

Characteristics Symbol		Test Condition		Ta = 25°C			Ta = -40~85°C		Unit	
				$V_{CC}(V)$	Min	Тур.	Max	Min	Max	Unit
High-level input voltage	V _{IH}	_		4.5~5.5	2.0	_	_	2.0	_	V
Low-level input voltage	V _{IL}	—		4.5~5.5	_	_	0.8	_	0.8	V
High-level output VOH	Veu	V _{IN} = V _{IH} or V _{IL}	I _{OH} = -20 μA	4.5	4.4	4.5		4.4	_	V
	VОН		$I_{OH} = -4 \text{ mA}$	4.5	4.18	4.31		4.13	_	
Low-level output V _{OL}	Max	V _{IN}	$I_{OL} = 20 \ \mu A$	4.5		0.0	0.1	_	0.1	V
	VOL = V	$= V_{IH} \text{ or } V_{IL}$	$I_{OL} = 4 \text{ mA}$	4.5		0.17	0.26	_	0.33	v
Input leakage current	I _{IN}	V _{IN} = V _{CC} or GND		5.5	_	_	±0.1	_	±1.0	μA
Quiescent supply current	ICC	V _{IN} = V _{CC} or GND		5.5	_		1.0	_	10.0	μA
	IC	Per input: $V_{IN} = 0.5 \text{ V or } 2.4 \text{ V}$ Other input: V_{CC} or GND		5.5		_	2.0	_	2.9	mA

AC Characteristics (C_L = 15 pF, V_{CC} = 5 V, Ta = 25°C, input: $t_r = t_f = 6$ ns)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Output transition time	t _{TLH}	—	—	4	8	ns
	t _{THL}					113
Propagation delay time	t _{pLH}	_		10	20	ns
	t _{pHL}			10	20	115

AC Characteristics ($C_L = 50 \text{ pF}$, input: $t_r = t_f = 6 \text{ ns}$)

Characteristics	Symbol	Test Condition		-	Га = 25°С)	Ta = −40~85°C		Unit
	Symbol		$V_{CC}(V)$	Min	Тур.	Max	Min	Max	Onit
Output transition time	t _{TLH}	_	4.5	_	8	15	_	19	ns
	t _{THL}		5.5		7	14		18	
Propagation delay time	t _{pLH}	—	4.5	_	13	19	_	24	20
	t _{pHL}		5.5		12	17		21	ns
Input capacitance	C _{IN}	—			5	10		10	pF
Power dissipation capacitance	C _{PD} (Note)	_		_	19	_		_	pF

Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

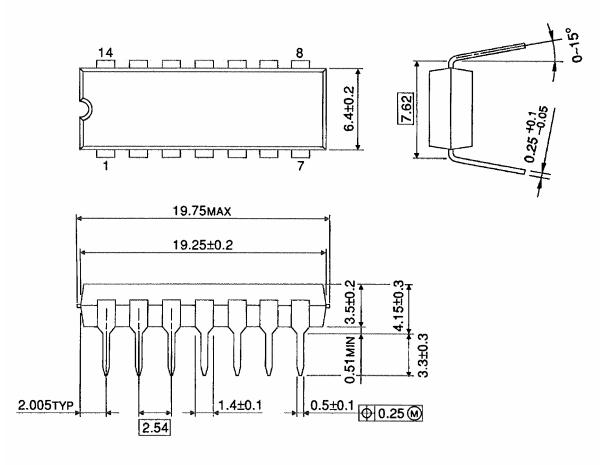
Average operating current can be obtained by the equation:

 I_{CC} (opr) = $C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/4$ (per gate)

Package Dimensions

DIP14-P-300-2.54

Unit : mm



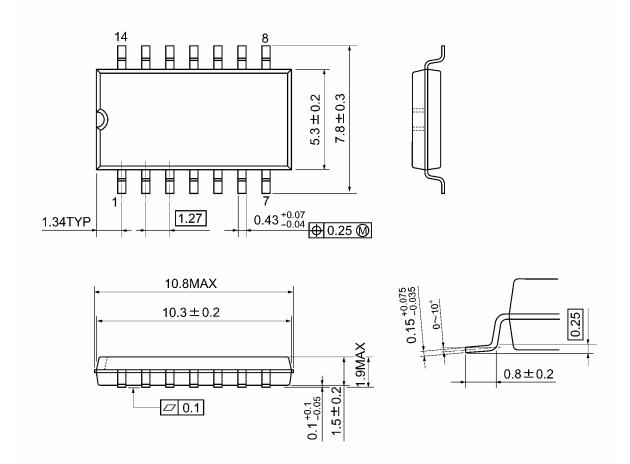
Weight: 0.96 g (typ.)



Package Dimensions

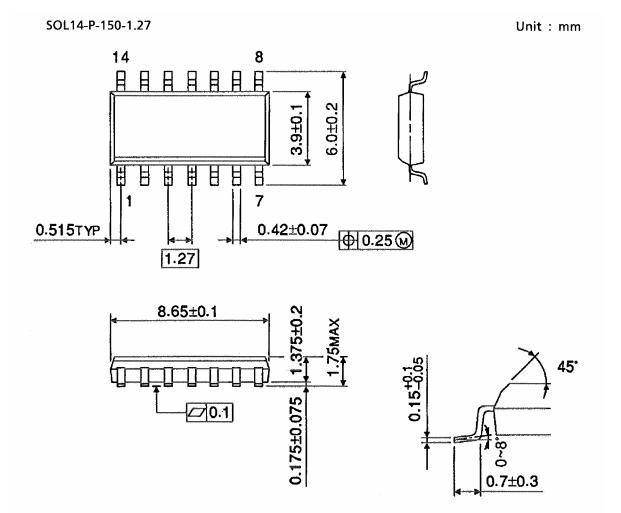
SOP14-P-300-1.27A

Unit: mm



Weight: 0.18 g (typ.)

Package Dimensions (Note)



Note: This package is not available in Japan.

Weight: 0.12 g (typ.)

RESTRICTIONS ON PRODUCT USE

20070701-EN GENERAL

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